

Press Release

DCG Systems Introduces Significant Upgrades to Its Yield Improvement, Fault Localization and Design Debug Products

FREMONT, CA--(Marketwire - November 3, 2008) - DCG Systems, Inc. today announced major upgrades to its comprehensive range of integrated analytical tools designed to meet the complex challenges facing manufacturers of today's advanced 45nm device technologies. DCG Systems products will be showcased at the 34th annual International Symposium for Testing and Failure Analysis (ISTFA 2008, Booth#403) to be held November 2-6 at the Oregon Convention Center, Portland, Oregon.

Meridian-IV is DCG Systems' newest generation spatial fault and defect localization instrument, and represents a number of significant enhancements to the successful Meridian platform. Among the improved features offered by the Meridian-IV:

- A high performance 1000 x 1000 pixel InGaAs detector.
- A lock-in amplifier for improved signal-to-noise ratio.
- Integration of the popular "Point & Click" Solid Immersion Lens (SIL).
- Image mosaic capability.

"We are pleased to be able to continue to offer our customers leading-edge capability to meet their most current semiconductor analytical needs," said Dr. Israel Niv, President and CEO of DCG Systems. "Our customers and our intellectual property are our greatest assets. The Meridian-IV represents our absolute commitment to continually improve our products based upon customer feedback."

DCG Systems continues to improve its other product lines as well. The OptiFIB-IV and P3X-IV focused ion-beam (FIB) instruments now offer an improved insulator deposition. Superior insulator characteristics provide more reliable FIB edits, thus increasing the already high edit success rates of these instruments.

The Ruby laser voltage prober now has improved capability for probing Silicon-on-Insulator (SOI) devices. SOI devices, which employ an insulating substrate layer, have historically been a challenge for laser voltage probing. Ruby's 20GHz bandwidth ensures high accuracy in signal rise time measurements.

About DCG Systems

DCG Systems, Inc., a privately held company headquartered in Fremont, California, is the leading provider of semiconductors debug and characterization solutions for the global semiconductor industry. With a commitment to applying innovative technology to improve time to yield and time to market, DCG Systems delivers competitive cost and performance advantages to integrated device manufacturers (IDMs), wafer foundries and fabless chip companies worldwide. DCG Systems is comprised of the former Schlumberger/NPT Test Probe Systems division, Optonics Inc. and Hypervision Inc., with an installed base of over 700 systems worldwide. For more information on DCG Systems, please visit <http://www.dcgsystems.com>.

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